

MC10E1652

5V, -5V Dual ECL Output Comparator with Latch

The MC10E1652 is fabricated using ON Semiconductor's advanced MOSAIC III process and is output compatible with 10H logic devices. In addition, the device is available in a 20-pin surface mount package. However, the MC10E1652 provides user programmable hysteresis.

The latch enable (\overline{LEN}_a and \overline{LEN}_b) input pins operate from standard ECL 10H logic levels. When the latch enable is at a logic high level, the MC10E1652 acts as a comparator; hence, Q will be at a logic high level if $V_1 > V_2$ (V_1 is more positive than V_2). \overline{Q} is the complement of Q. When the latch enable input goes to a low logic level, the outputs are latched in their present state, providing the latch enable setup and hold time constraints are met. The level of input hysteresis is controlled by applying a bias voltage to the HYS pin.

Features

- Typical 3.0 dB Bandwidth > 1.0 GHz
- Typical V to Q Propagation Delay of 775 ps
- Typical Output Rise/Fall of 350 ps
- Common Mode Range -2.0 V to +3.0 V
- Individual Latch Enables
- Differential Outputs
- Operating Mode: $V_{CC} = 5.0$ V, $V_{EE} = -5.2$ V, GND = 0 V
- Programmable Input Hysteresis
- No Internal Input Pulldown Resistors
- ESD Protection: Human Body Model; > 2 kV, Machine Model; > 100 V
- Meets or Exceeds JEDEC Spec EIA/JESD78 IC Latchup Test
- Moisture Sensitivity Level 3
For Additional Information, see Application Note AND8003/D
- Flammability Rating: UL 94 V-O @ 0.125 in, Oxygen Index: 28 to 34
- Transistor Count = 85 devices
- These are Pb-Free Devices*



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MARKING DIAGRAM



PLCC-20
FN SUFFIX
CASE 775



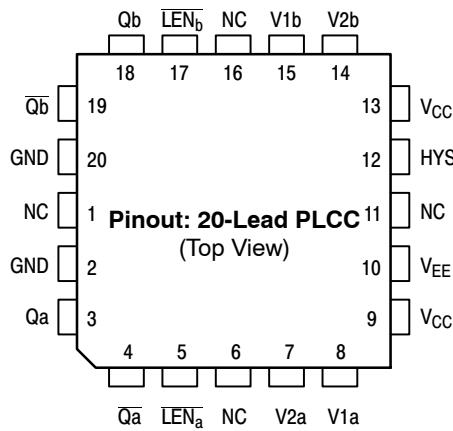
A = Assembly Location
WL = Wafer Lot
YY = Year
WW = Work Week
G = Pb-Free Package

ORDERING INFORMATION

See detailed ordering and shipping information in the package dimensions section on page 7 of this data sheet.

*For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

MC10E1652



* All V_{CC} and V_{CCO} pins are NOT tied together on the die.

Warning: All V_{CC} , GND, and V_{EE} pins must be externally connected to Power Supply to guarantee proper operation.

Figure 1. Logic Diagrams and Pinout Assignments

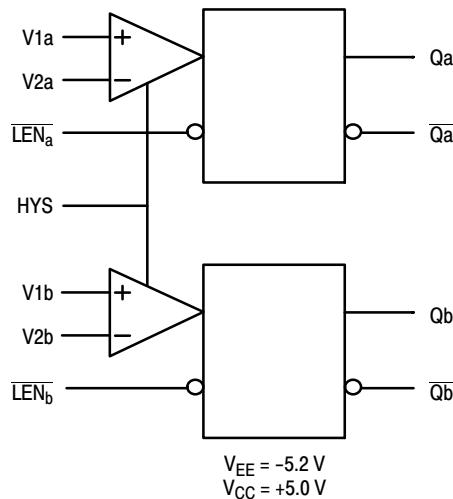


Figure 2. Logic Diagram

Table 1. PIN DESCRIPTION

PIN	FUNCTION
Q_a, \bar{Q}_a	ECL Differential Outputs (a)
Q_b, \bar{Q}_b	ECL Differential Outputs (b)
LEN_a, \bar{LEN}_b	ECL Latch Enable
V_{1a}, V_{1b}	Input Comparator 1
V_{2a}, V_{2b}	Input Comparator 2
HYS	Hysteresis Bias Voltage Control Input
V_{CC}	Positive Supply
V_{EE}	Negative Supply
NC	No Connect
GND	Ground

Table 2. FUNCTION TABLE

LEN	V_1, V_2	Function
H	$V_1 > V_2$	H
H	$V_1 < V_2$	L
L	X	Latched

Table 3. MAXIMUM RATINGS

Symbol	Parameter	Condition 1	Condition 2	Rating	Units
VSUP	Total Supply Voltage	$ V_{EE} + V_{CC} $		12.0	V
VPP	Differential Input Voltage	$ V_1 - V_2 $		3.7	V
V_I	Input Voltage			$V_{EE} \leq V_I \leq V_{CC}$	V
I_{out}	Output Current	Continuous Surge		50 100	mA mA
I_{BB}	V_{BB} Sink/Source			± 0.5	mA
TA	Operating Temperature Range			0 to +85	°C
T_{stg}	Storage Temperature Range			-65 to +150	°C
θ_{JA}	Thermal Resistance (Junction to Ambient)	0 LFPM 500 LFPM	28 PLCC 28 PLCC	63.5 43.5	°C/W °C/W
θ_{JC}	Thermal Resistance (Junction to Case)	std bd	28 PLCC	22 to 26	°C/W
V_{EE}	Operating Range	GND = 0 V		-4.2 to -5.7	V
T_{sol}	Wave Solder	Pb-Free	≤ 3 sec @ 260°C	265	°C

Stresses exceeding Maximum Ratings may damage the device. Maximum Ratings are stress ratings only. Functional operation above the Recommended Operating Conditions is not implied. Extended exposure to stresses above the Recommended Operating Conditions may affect device reliability.

Table 4. DC CHARACTERISTICS $V_{CC} = +5.0$ V $\pm 5\%$; $V_{EE} = -5.2$ V $\pm 5\%$, $V_{CC} = 0$ V (Note 1)

Symbol	Characteristic	0°C			25°C			85°C			Unit
		Min	Typ	Max	Min	Typ	Max	Min	Typ	Max	
V_{OH}	Output HIGH Voltage (Note 2)	-1020		-840	-980		-810	-920		-735	mV
V_{OL}	Output Low Voltage (Note 2)	-1950		-1630	-1950		-1630	-1950		-1600	mV
V_{IL}	Input LOW Voltage (LEN)	-1.95		-1.48	-1.95		-1.48	-1.95		-1.45	mV
V_{IH}	Input HIGH Voltage (LEN)	-1.17		-0.84	-1.13		-0.81	-1.07		-0.735	mV
I_{II} I_{IH}	Input Current (V1, V2) Input HIGH Current (LEN)			65 150			65 150			65 150	µA
I_{CC} I_{EE}	Positive Supply Current Negative Supply Current			50 -55			50 -55			50 -55	mA
VMCR	Common Mode Range (Note 3)	-2.0		3.0	-2.0		3.0	-2.0		3.0	V
Hys	Hysteresis (Note 4)		27			27			30		mV
V_{skew}	Hysteresis Skew (Note 5)		-1.0			-1.0			0		mV
C_{in}	Input Capacitance	PLCC		2			2			2	pF

NOTE: Device will meet the specifications after thermal equilibrium has been established when mounted in a test socket or printed circuit board with maintained transverse airflow greater than 500 lfpm. Electrical parameters are guaranteed only over the declared operating temperature range. Functional operation of the device exceeding these conditions is not implied. Device specification limit values are applied individually under normal operating conditions and not valid simultaneously.

1. Input V_{IL} and V_{IH} parameters vary 1:1 with V_{CC} . Output V_{OH} and V_{OL} parameters vary 1:1 with GND.
2. Outputs are terminated through a 50 ohm resistor to GND-2 volts.
3. VMCR Min varies 1:1 with V_{EE} ; Max varies 1:1 with V_{CC} .
4. The HYS pin programming characterization information is shown in Figure 2. The hysteresis values indicated in the data sheet are for the condition in which the voltage on the HYS pin is set to V_{EE} .
5. Hysteresis skew (V_{skew}) is provided to indicate the offset of the hysteresis window. For example, at 25°C the nominal hysteresis value is 27 mV and the V_{skew} value indicates that the hysteresis was skewed from the reference level by 1 mV in the negative direction. Hence the hysteresis window ranged from 14 mV below the reference level to 13 mV above the reference level. All hysteresis measurements were determined using a reference voltage of 0 mV. The hysteresis skew values apply over the programming range shown in Figure 2.

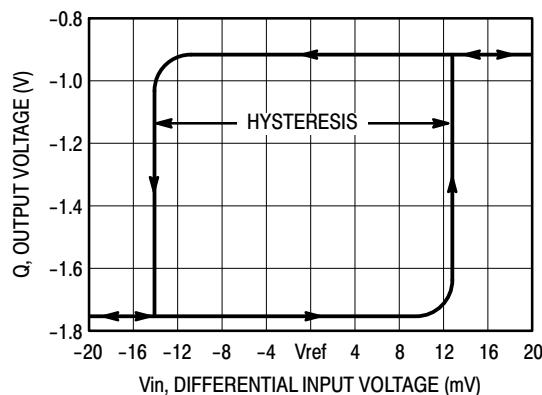


Figure 3. Typical Hysteresis Curve

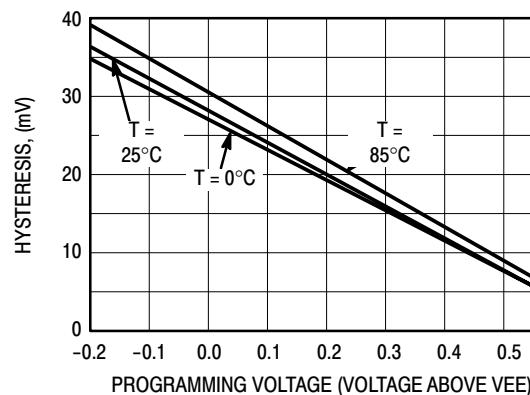


Figure 4. Hysteresis Programming Voltage

Table 5. AC CHARACTERISTICS $V_{CC} = +5.0 \text{ V} \pm 5\%$; $V_{EE} = -5.2 \text{ V} \pm 5\%$, $V_{CC} = 0 \text{ V}$ (Note 6)

Symbol	Characteristic	0°C			25°C			85°C			Unit
		Min	Typ	Max	Min	Typ	Max	Min	Typ	Max	
f_{MAX}	Maximum Toggle Frequency		TBD			> 1.0			TBD		GHz
t_{PLH}	Propagation Delay to Output (Note 7)										
	V to Q	750	900	1050	775	925	1075	850	1025	1200	ps
	\overline{LEN} to Q	550	725	900	550	750	900	650	825	1000	
t_s	Setup Time										ps
	V	450	300		450	300		550	350		
t_h	Enable Hold Time										ps
	V	-50	-250		-50	-250		-100	-250		
t_{pw}	Minimum Pulse Width										ps
	\overline{LEN}	400			400			400			
t_{skew}	Within Device Skew (Note 8)				15			15			ps
t_{JITTER}	Cycle-to-Cycle Jitter				TBD			TBD			ps
T_{DE}	Delay Dispersion										ps
	(ECL Levels) (Notes 9, 10)										
	(Notes 9, 11)							100			
							60				
T_{DL}	Delay Dispersion							350			ps
	(TTL Levels) (Notes 12, 13)							100			
	(Notes 11, 12)										
V_{PP}	Differential Input Voltage $ V_1 - V_2 $			3.7			3.7		3.7	V	
t_r	Rise/Fall Times (20-80%)	225	325	475	225	325	475	250	375	500	ps
t_f											

NOTE: Device will meet the specifications after thermal equilibrium has been established when mounted in a test socket or printed circuit board with maintained transverse airflow greater than 500 lfm. Electrical parameters are guaranteed only over the declared operating temperature range. Functional operation of the device exceeding these conditions is not implied. Device specification limit values are applied individually under normal operating conditions and not valid simultaneously.

6. Input V_{IL} and V_{IH} parameters vary 1:1 with V_{CC} . Output V_{OH} and V_{OL} parameters vary 1:1 with GND.
7. The propagation delay is measured from the crosspoint of the input signal and the threshold value to the crosspoint of the Q and \overline{Q} output signals. For propagation delay measurements the threshold level (V_{THR}) is centered about an 850 mV input logic swing with a slew rate of 0.75 V/NS. There is an insignificant change in the propagation delay over the input common mode range.
8. t_{skew} is the propagation delay skew between comparator A and comparator B for a particular part under identical input conditions.
9. Refer to Figure 4 and note that the input is at 850 mV ECL levels with the input threshold range between the 20% and 80% points. The delay is measured from the crosspoint of the input signal and the threshold value to the crosspoint of the Q and \overline{Q} output signals.
10. The slew rate is 0.25 V/NS for input rising edges.
11. The slew rate is 0.75 V/NS for input rising edges.
12. Refer to Figure 5 and note that the input is at 2.5 V TTL levels with the input threshold range between the 20% and 80% points. The delay is measured from the crosspoint of the input signal and the threshold value to the crosspoint of the Q and \overline{Q} output signals.
13. The slew rate is 0.3 V/NS for input rising edges.

APPLICATIONS INFORMATION

The timing diagram (Figure 5.) is presented to illustrate the MC10E1652's compare and latch features. When the signal on the \overline{LEN} pin is at a logic high level, the device is operating in the "compare mode," and the signal on the input arrives at the output after a nominal propagation delay (t_{PHL} , t_{PLH}). The input signal must be asserted for a time, t_s , prior to the negative going transition on \overline{LEN} and held for a time, t_h , after the \overline{LEN} transition. After time t_h , the latch is operating in the "latch mode," thus transitions on the input do not appear at the output. The device continues to operate in the "latch mode" until the latch is asserted once again. Moreover, the \overline{LEN} pulse must meet the minimum pulse width (t_{pw}) requirement to effect the correct input-output relationship. Note that the \overline{LEN} waveform in Figure 5. shows the \overline{LEN} signal swinging around a reference labeled $V_{BB_{INT}}$; this waveform emphasizes the requirement that \overline{LEN} follow typical ECL 10KH logic levels because

$V_{BB_{INT}}$ is the internally generated reference level, hence is nominally at the ECL V_{BB} level.

Finally, V_{OD} is the input voltage overdrive and represents the voltage level beyond the threshold level (V_{THR}) to which the input is driven. As an example, if the threshold level is set on one of the comparator inputs as 80 mV and the input signal swing on the complementary input is from zero to 100 mV, the positive going overdrive would be 20 mV and the negative going overdrive would be 80 mV. The result of differing overdrive levels is that the devices have shorter propagation delays with greater overdrive because the threshold level is crossed sooner than the case of lower overdrive levels. Typically, semiconductor manufacturers refer to the threshold voltage as the input offset voltage (V_{OS}) since the threshold voltage is the sum of the externally supplied reference voltage and inherent device offset voltage.

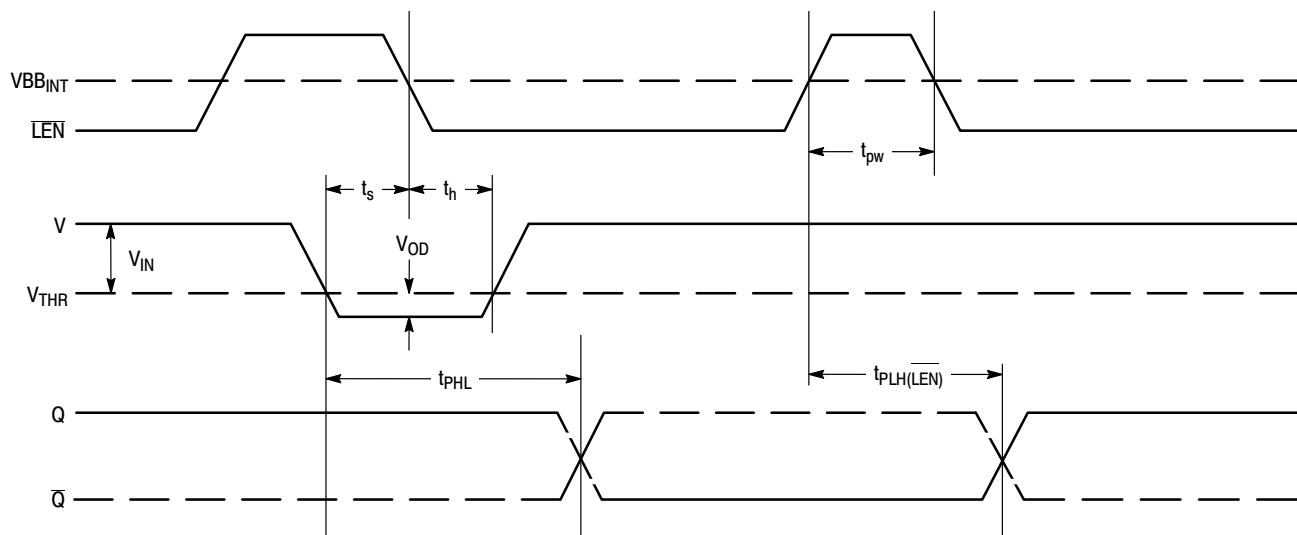


Figure 5. Input/Output Timing Diagram

DELAY DISPERSION

Under a constant set of input conditions comparators have a specified nominal propagation delay. However, since propagation delay is a function of input slew rate and input voltage overdrive the delay dispersion parameters, T_{DE} and T_{DT} , are provided to allow the user to adjust for these variables (where T_{DE} and T_{DT} apply to inputs with standard ECL and TTL levels, respectively).

Figure 6. and Figure 7. define a range of input conditions which incorporate varying input slew rates and input voltage overdrive. For input parameters that adhere to these constraints the propagation delay can be described as:

$$T_{NOM} \pm T_{DE} \text{ (or } T_{DT})$$

where T_{NOM} is the nominal propagation delay. T_{NOM} accounts for nonuniformity introduced by temperature and voltage variability, whereas the delay dispersion parameter takes into consideration input slew rate and input voltage overdrive variability. Thus a modified propagation delay can be approximated to account for the effects of input conditions that differ from those under which the parts were tested. For example, an application may specify an ECL input with a slew rate of 0.25 V/NS, an overdrive of 17 mV and a temperature of 25°C, the delay dispersion parameter would be 100 ps. The modified propagation delay would be

$$775 \text{ ps} \pm 100 \text{ ps}$$

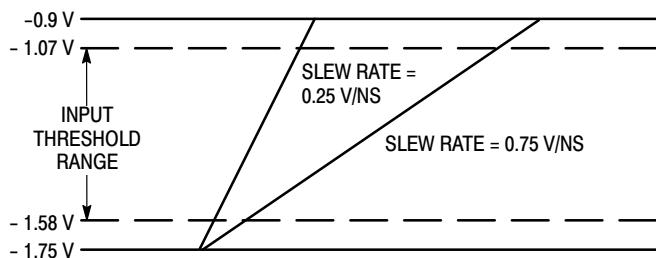


Figure 6. ECL Dispersion Test Input Conditions

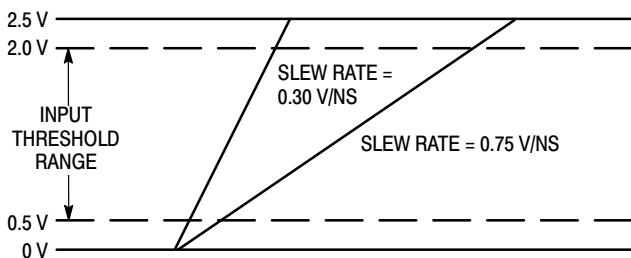
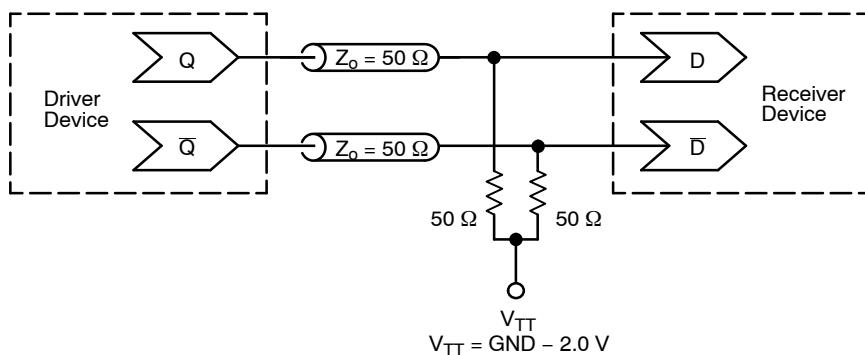


Figure 7. TTL Dispersion Test Input Conditions



**Figure 8. Typical Termination for Output Driver and Device Evaluation
(See Application Note AND8020 – Termination of ECL Logic Devices.)**

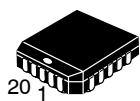
ORDERING INFORMATION

Device	Package	Shipping [†]
MC10E1652FNG	PLCC-20 (Pb-Free)	46 Units / Rail
MC10E1652FNR2G	PLCC-20 (Pb-Free)	500 / Tape & Reel

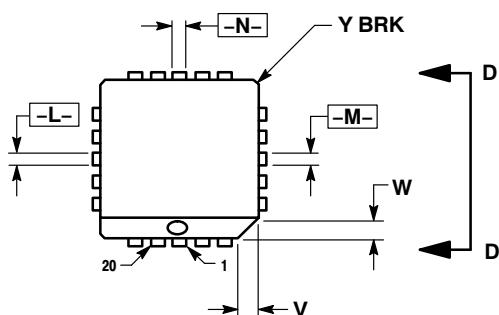
[†]For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.

Resource Reference of Application Notes

- AN1405/D** – ECL Clock Distribution Techniques
- AN1406/D** – Designing with PECL (ECL at +5.0 V)
- AN1503/D** – ECLinPS™ I/O SPiCE Modeling Kit
- AN1504/D** – Metastability and the ECLinPS Family
- AN1568/D** – Interfacing Between LVDS and ECL
- AN1672/D** – The ECL Translator Guide
- AND8001/D** – Odd Number Counters Design
- AND8002/D** – Marking and Date Codes
- AND8020/D** – Termination of ECL Logic Devices
- AND8066/D** – Interfacing with ECLinPS
- AND8090/D** – AC Characteristics of ECL Devices

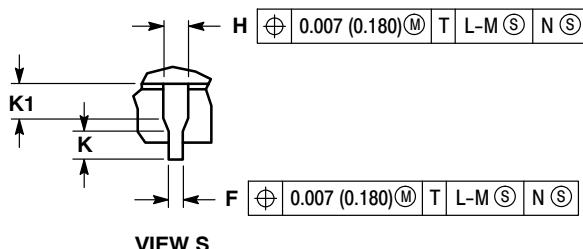
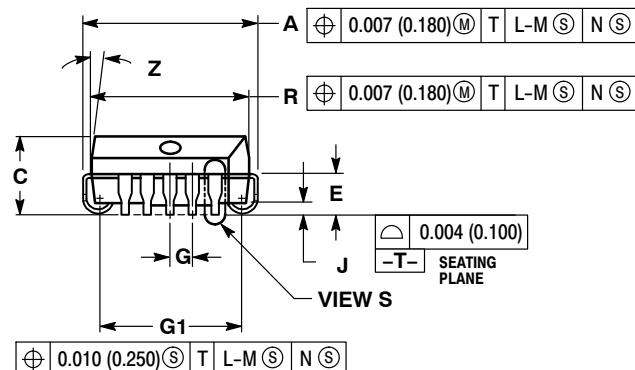
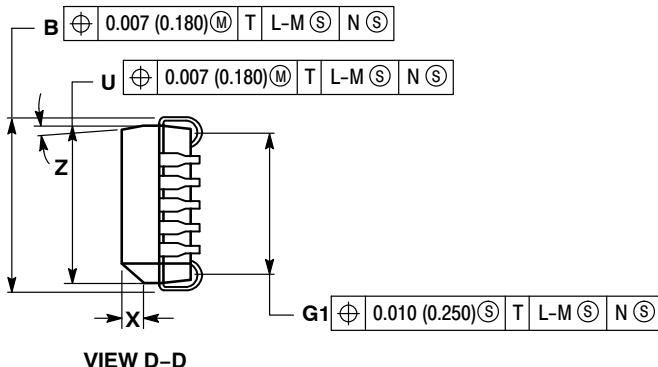


SCALE 1:1



20 LEAD PLLC
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ISSUE F

DATE 25 JUL 2008

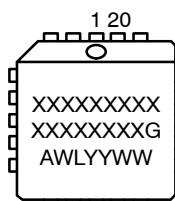


NOTES:

1. DIMENSIONS AND TOLERANCING PER ANSI Y14.5M, 1982.
2. DIMENSIONS IN INCHES.
3. DATUMS $-L-$, $-M-$, AND $-N-$ DETERMINED WHERE TOP OF LEAD SHOULDER EXITS PLASTIC BODY AT MOLD PARTING LINE.
4. DIMENSION G1, TRUE POSITION TO BE MEASURED AT DATUM $-T-$, SEATING PLANE.
5. DIMENSIONS R AND U DO NOT INCLUDE MOLD FLASH. ALLOWABLE MOLD FLASH IS 0.010 (0.250) PER SIDE.
6. DIMENSIONS IN THE PACKAGE TOP MAY BE SMALLER THAN THE PACKAGE BOTTOM BY UP TO 0.012 (0.300). DIMENSIONS R AND U ARE DETERMINED AT THE OUTERMOST EXTREMES OF THE PLASTIC BODY EXCLUSIVE OF MOLD FLASH, TIE BAR BURRS, GATE BURRS AND INTERLEAD FLASH, BUT INCLUDING ANY MISMATCH BETWEEN THE TOP AND BOTTOM OF THE PLASTIC BODY.
7. DIMENSION H DOES NOT INCLUDE DAMBAR PROTRUSION OR INTRUSION. THE DAMBAR PROTRUSION(S) SHALL NOT CAUSE THE H DIMENSION TO BE GREATER THAN 0.037 (0.940). THE DAMBAR INTRUSION(S) SHALL NOT CAUSE THE H DIMENSION TO BE SMALLER THAN 0.025 (0.635).

DIM	INCHES		MILLIMETERS	
	MIN	MAX	MIN	MAX
A	0.385	0.395	9.78	10.03
B	0.385	0.395	9.78	10.03
C	0.165	0.180	4.20	4.57
E	0.090	0.110	2.29	2.79
F	0.013	0.021	0.33	0.53
G	0.050	BSC	1.27	BSC
H	0.026	0.032	0.66	0.81
J	0.020	---	0.51	---
K	0.025	---	0.64	---
R	0.350	0.356	8.89	9.04
U	0.350	0.356	8.89	9.04
V	0.042	0.048	1.07	1.21
W	0.042	0.048	1.07	1.21
X	0.042	0.056	1.07	1.42
Y	---	0.020	---	0.50
Z	2°	10°	2°	10°
G1	0.310	0.330	7.88	8.38
K1	0.040	---	1.02	---

**GENERIC
MARKING DIAGRAM***



XXXXX = Specific Device Code
A = Assembly Location
WL = Wafer Lot
YY = Year
WW = Work Week
G = Pb-Free Package

*This information is generic. Please refer to device data sheet for actual part marking.
Pb-Free indicator, "G" or microdot "■", may or may not be present.

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